



e.MMC 4.51 I/F

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SanDisk Corporation

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TABLE OF CONTENTS

| 1. | Intro | duction | 5 |
|----|-------|---|----|
| | 1.1. | General Description | 5 |
| | 1.2. | Plug-and-Play Integration | 5 |
| | 1.3. | Feature Overview | 6 |
| | 1.4. | Functional Description | 7 |
| | 1.5. | Technology Independence | 7 |
| | 1.6. | Defect and Error Management | 7 |
| | 1.7. | MMC bus and Power Lines | 7 |
| | | 1.7.1. Bus operating conditions | 8 |
| 2. | | MC4.51 Selected Features Overview | |
| | 2.1. | Discard | 10 |
| | 2.2. | Power Off Notifications | 10 |
| | 2.3. | Packed Commands | 10 |
| | 2.4. | Boot partitions Size | 10 |
| | 2.5. | Automatic Sleep Mode | 10 |
| | 2.6. | Sleep (CMD5) | 11 |
| | 2.7. | Enhanced Reliable Write | 11 |
| | 2.8. | Secure Erase | 11 |
| | 2.9. | Secure Trim | 12 |
| | 2.10 | . Trim | 12 |
| | 2.11 | . Partition management | 12 |
| | 2.12 | . Device Health | 13 |
| | 2.13 | . Enhanced Write Protection | 13 |
| | 2.14 | . High Priority Interrupt (HPI) | 13 |
| | 2.15 | . H/W Reset | 14 |
| | 2.16 | . DDR I/F | 14 |
| 3. | Prod | luct Specifications | 15 |
| | 3.1. | Typical Power Requirements | 15 |
| | 3.2. | Operating Conditions | 15 |
| | | 3.2.1. Operating and Storage Temperature Specifications | |
| | | 3.2.2. Moisture Sensitivity | |
| | | System Performance | |
| 4. | Phys | sical Specifications | 17 |

| 5. | Inter | face D | Description | 19 |
|----|-------|----------|-----------------------------------|----|
| | 5.1. | MMC | I/F Ball Array 153 ball | 19 |
| | 5.2. | Pins a | and Signal Description 153 balls | 20 |
| | 5.3. | iNANE | O Registers | 21 |
| | | | OCR Register | |
| | | | CID Register | |
| | | | DSR Register | |
| | | 5.3.4. | CSD Register | 22 |
| | | 5.3.5. | EXT_CSD Register | 23 |
| 6. | Pow | er Deli | very and Capacitor Specifications | 28 |
| | 6.1. | SanDi | isk iNAND UltraPower Domains | 28 |
| | 6.2. | Capac | citor Connection Guidelines | 28 |
| | | | VDDi Connections | |
| | | 6.2.2. | VCC and VCCQ Connections | 28 |
| 7. | Mari | king | | 30 |
| 8. | Orde | ering In | nformation | 31 |
| | | • | ct Us | |

1. Introduction

1.1. General Description

iNAND Ultra is an Embedded Flash Drive (EFD) designed for mobile handsets and consumer electronic devices. iNAND Ultra is a hybrid device combining an embedded thin flash controller and standard MLC NAND flash memory, with an industry standard e.MMC 4.51¹ interface.

Empowered with a new e.MMC4.51 feature set such as Power Off Notifications and Packed commands, as well as legacy e.MMC4.41 features such as Boot and RPMB partitions, HPI, and HW Reset the iNAND Ultra e.MMC is the optimal device for reliable code and data storage.

Designed specifically for mobile multimedia applications, iNAND Ultra is the most mature on board MMC device since 2005, providing mass storage of up to 128GB in JEDEC compatible form factors, with low power consumption and high performance - an ideal solution for multimedia handsets of 2.5G, 3G, 3.5G and 4G.

In addition to the high reliability and high system performance offered by the current iNAND family of products, iNAND Ultra offers plug-and-play integration and support for multiple NAND technology transitions, as well as features such as advanced power management scheme.

iNAND Ultra uses advanced Multi-Level Cell (MLC) NAND flash technology, enhanced by SanDisk's embedded flash management software running as firmware on the flash controller.

iNAND Ultra architecture and embedded firmware fully emulates a hard disk to the host processor, enabling read/write operations that are identical to a standard, sector-based hard drive. In addition, SanDisk firmware employs patented methods, such as virtual mapping, dynamic and static wear-leveling, and automatic block management to ensure high data reliability and maximize flash life expectancy.

SanDisk iNAND Ultra provides 4GB and 8GB of memory for use in mass storage applications. In addition to the mass-storage-specific flash memory chip, iNAND Ultra includes an intelligent controller, which manages interface protocols, data storage and retrieval, error correction code (ECC) algorithms, defect handling and diagnostics, power management and clock control.

iNAND Ultra enables multimedia driven applications such as music, photo, video, TV, GPS, games, email, office and other applications.

The breakthrough in performance and design makes iNAND Ultra the ideal solution for mobile handset vendors, portable navigation and Automotive Infotainment vendors who require easy integration, fast time to market and high-capacity.

1.2. Plug-and-Play Integration

iNAND optimized architecture eliminates the need for complicated software integration and testing processes and enables a practically plug-and-play integration in the system. The replacement of one iNAND device with another of a newer generation requires virtually no changes to the host. This makes iNAND the perfect solution for platforms and reference designs, as it allows for the

¹ Compatible to JESD84-B451

utilization of more advanced NAND Flash technology with minimal integration or qualification efforts.

SanDisk iNAND Ultra is well-suited to meet the needs of small, low power, electronic devices. With JEDEC form factors measuring 11.5x13mm (153 balls) form factor compatible with 0.5mm ball pitch, iNAND Ultra is fit for a wide variety of portable devices such as multi-media mobile handsets, personal media players, GPS devices and Automotive infotainment (car multimedia and car navigation).

To support this wide range of applications, iNAND Ultra is offered with an MMC Interface.

The MMC interface allows for easy integration into any design, regardless of the host (chipset) type used. All device and interface configuration data (such as maximum frequency and device identification) are stored on the device.

Figure 1 shows a block diagram of the SanDisk iNAND Ultra with MMC Interface.

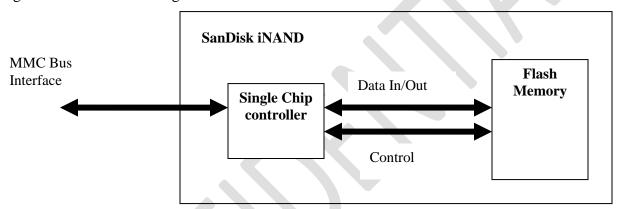


Figure 1 - SanDisk iNAND Ultra with MMC I/F Block Diagram

1.3. Feature Overview

SanDisk iNAND Extreme, with MMC interface, features include the following:

- Memory controller and NAND flash
- Complies with e.MMC Specification Ver. 4.51²
- Mechanical design complies with JEDED MO-276C Specification
- Offered in two TFBGA packages of e.MMC 4.51³
 - o 11.5mm x 13mm x 1.0mm
- Operating temperature range: -25C° to +85C°
- Dual power system
- Core voltage (VCC) 2.7-3.6v
- I/O (VCCQ) voltage, either: 1.7-1.95v or 2.7-3.6v

² Refer to JEDEC Standards No. JESD84-B451

³ Refer to JEDEC Standards No. JESD84-C441

- Up to 8GB of data storage.
- Supports three data bus widths: 1bit (default), 4bit, 8bit.
- Variable clock frequencies of 0-20 MHz, 0-26 MHz (default), 0-52 MHz (high-speed)
- Up to 104 MB/sec bus transfer rate, using 8 parallel data lines at 52 MHz, DDR Mode
- Correction of memory field errors
- Designed for portable and stationary applications that require high performance and reliable data storage

1.4. Functional Description

SanDisk iNAND Ultra contains a high-level, intelligent subsystem as shown in Figure 1. This intelligent (microprocessor) subsystem provides many capabilities not found in other types of storage devices. These capabilities include:

- Host independence from details of erasing and programming flash memory
- Sophisticated system for managing defects
- Sophisticated system for error recovery including a powerful ECC
- Power management for low power operation

1.5. Technology Independence

SanDisk iNAND *Ultra* uses 512 bytes as sector size. To write or read a sector (or multiple sectors), the host software simply issues a read or write command to the device. The command contains the address and number of sectors to write or read. The host software then waits for the command to complete.

There is no host software involvement in the details of flash operations such as erase, program or read. This is extremely important since flash devices are becoming increasingly complex with current advanced NAND MLC processes. Because iNAND uses an intelligent on-board controller, host system software will not need to be updated as new flash memory evolves. In other words, systems that support iNAND technology today will be able to access future SanDisk devices built with new flash technology without having to update or change the host software.

1.6. Defect and Error Management

The SanDisk iNAND Ultra contains a sophisticated defect and error management system. If necessary, iNAND will rewrite data from a defective sector to a good sector. This is completely transparent to the host and does not consume any user data space. In the extremely rare case that a read error does occur, iNAND has innovative algorithms to recover the data. These defect and error management systems, coupled with the solid state construction, give SanDisk iNAND Ultra unparalleled reliability.

1.7. MMC bus and Power Lines

SanDisk iNAND Ultra with MMC interface supports the MMC protocol. For more details regarding these buses refer to JEDEC standards No. JESD84-B451.

The iNAND bus has the following communication and power lines:

- CMD: Command is a bidirectional signal. The host and iNAND operate in two modes, open drain and push-pull.
- DAT0-7: Data lines are bidirectional signals. Host and iNAND operate in push-pull mode.
- CLK: Clock input.
- RST_n: Hardware Reset Input
- VCCQ: VCCQ is the power supply line for host interface.
- VCC: VCC is the power supply line for internal flash memory.
- VDDi: VDDi is iNAND's internal power node, not the power supply. Connect 0.1uF capacitor from VDDi to ground.
- VSS, VSSQ: ground lines.

1.7.1. Bus operating conditions

Table 1 - Bus operating conditions

| Table 1 - Bus operating conditions | | | | | |
|--|------|----------|------|--|--|
| Parameter | Min | Max | Unit | | |
| Peak voltage on all lines | -0.5 | VCCQ+0.5 | V | | |
| Input Leakage Current (before initializing and/or connecting the internal pull-up resistors) | -100 | 100 | μΑ | | |
| Input Leakage Current (after changing the bus width and disconnecting the internal pull-up resistors) | -2 | 2 | μΑ | | |
| Output Leakage Current (before initializing and/or connecting the internal pull-up resistors) | -100 | 100 | μΑ | | |
| Output Leakage Current (after changing the bus width and disconnecting the internal pull-up resistors) | -2 | 2 | μА | | |

Table 2 - Power supply voltage

| Parameter Syr | nbol Min | Max | Unit |
|---------------|----------|-----|------|
|---------------|----------|-----|------|

| | VCCQ (Low) | 1.65 | 1.95 | V |
|-----------------|--------------|------|------|---|
| Complex Valtage | VCCQ (High) | 2.7 | 3.6 | V |
| Supply Voltage | VCC | 2.7 | 3.6 | V |
| | VSS-VSSQ | -0.5 | 0.5 | V |



2. E.MMC4.51 SELECTED FEATURES OVERVIEW

2.1. Discard

iNAND supports discard command as defined in e.MMC4.51 spec⁴. This command allows the host to identify data which is not needed, without requiring the device to remove the data from the Media. It is highly recommended for use to guarantee optimal performance of iNAND and reduce amount of housekeeping operation.

2.2. Power Off Notifications

iNAND supports power off notifications as defined in e.MMC4.51 spec⁵. The usage of power off notifications allows the device to prepare itself to power off, and improve user experience during power-on.

- Latency overall user experience is improved. Device returns quicker from each write operation
- **Burst performance** is improved performing housekeeping allows us to better prepare for the next burst operations. (Cleaning up the SLC cache for future usage)
- **Graceful shutdown** power off notification itself allows the device to shutdown properly and save important data for fast boot time on the next power cycle

2.3. Packed Commands

To enable optimal system performance, iNAND supports packed commands as defined in e.MMC4.51 spec⁶. It allows the host to pack Read or Write commands into groups (of single type of operation) and transfer these to the device in a single transfer on the bus. Thus, it allows reducing overall bus overheads.

Faster sequential write performance on platform level using packed CMD

- Convert packed sequential commands to a single internal write. (ie. 8x128K packed writes become a single 1MB write)
- Hides host TAT, pipelines writes

2.4. Boot partitions Size

iNAND supports e.MMC 4.51 boot operation modes.

Boot partition size is reflected in BOOT_SIZE_MULT register value in extended CSD.

2.5. Automatic Sleep Mode

A unique feature of iNAND is automatic entrance and exit from sleep mode. Upon completion of an operation, iNAND enters sleep mode to conserve power if no further commands are received.

⁴ For additional information refer to JEDEC Standard No. JESD84-B451

⁵ For additional information refer to JEDEC Standard No. JESD84-B451

⁶ For additional information refer to JEDEC Standard No. JESD84-B451

Typically the entrance to sleep mode occurs after 10ms, max value entering sleep mode is 850ms due to housekeeping operation. The host does not have to take any action for this to occur, however, in order to achieve the lowest sleep current, the host needs to shut down its clock to the memory device. In most systems, embedded devices are in sleep mode except when accessed by the host, thus conserving power. When the host is ready to access a memory device in sleep mode, any command issued to it will cause it to exit sleep and respond immediately.

2.6. Sleep (CMD5)

An iNAND device may be switched between a Sleep and a Standby state using the SLEEP/AWAKE (CMD5). In the Sleep state the power consumption of the memory device is minimized and the memory device reacts only to the commands RESET (CMD0) and SLEEP/AWAKE (CMD5). All the other commands are ignored by the memory device.

The Vcc power supply may be switched off in Sleep state is to enable even further system power consumption saving.

For additional information please refer JESD84-B451 section number 6.6.28.

2.7. Enhanced Reliable Write

iNAND supports enhanced reliable write as defined in e.MMC 4.51 spec⁷.

Enhanced reliable write is a special write mode in which the old data pointed to by a logical address must remain unchanged until the new data written to same logical address has been successfully programmed. This is to ensure that the target address updated by the reliable write transaction never contains undefined data. When writing in reliable write, data will remain valid even if a sudden power loss occurs during programming.

2.8. Secure Erase

For backward compatibility reasons, in addition to the standard erase command the iNAND supports the optional Secure Erase command⁸.

The Secure Erase command differs from the basic Erase command in that it requires the iNAND to execute the erase operation on the memory array when the command is issued and requires the iNAND and host to wait until the operation is complete before moving to the next iNAND operation.

The secure erase command requires the iNAND to perform a secure purge operation on the erase groups, and copy items identified for erase, in those erase groups.

A purge operation is defined as overwriting addressable locations with a single character and then performing an erase.

This new command meets high security application requirements (e,g, those used by military and government customers) that once data has been erased, it can no longer be retrieved from the device.

⁷ For additional information refer to JEDEC Standards No. JESD84-B451

⁸ For additional information refer to JEDEC Standards No. JESD84-B451

2.9. Secure Trim

For backward compatibility reasons, iNAND support Secure Trim command. The Secure Trim⁹ command is similar to the Secure Erase command but performs a secure purge operation on write blocks instead of erase groups. The size of a write block in the iNAND device is 512B

2.10. Trim

The Trim function is similar to the Erase command but applies the erase operation to write blocks instead of erase groups. The size of a write block in the INAND device is 512B

For additional information on the Trim function, refer to JEDEC standards No. JESD84-B451

2.11. Partition management

The iNAND offers the possibility for the host to configure additional split local memory partitions with independent addressable space starting from logical address 0x00000000 for different usage models. Therefore memory block area scan be classified as follows¹⁰:

- Factory configuration supplies two boot partitions (refer to section 2.1) implemented as enhanced storage media and one RPMB partitioning of 2MB in size.
- Up to four General Purpose Area Partitions can be configured to store user data or sensitive data, or for other host usage models. The size of these partitions is a multiple of the write protect group. Size can be programmed once in device life-cycle (one-time programmable).

⁹ For additional information refer to JEDEC Standards No. JESD84-B451

¹⁰ For additional information refer to JEDEC Standards No. JESD84-B451

2.12. Device Health

Device Health is SanDisk proprietary feature and is similar to SMART feature of modern hard disks, it provides only vital NAND flash program/erase cycles information in percentage of useful flash life span.

Host can query Device Health information utilizing standard MMC command, CMD_8, to get extended CSD structure. Device health feature will provide % of the wear of the device in 10% fragments.

The following 2 Extended CSD fields will hold the average percentage of usage for an iNAND device. Each one holds a value for of the specified memory types:

- ☐ MLC User Area
- ☐ SLC Internal memory such as Binary Cache

| Name | Field | Size (Byte) | Cell Type | Hex Offset (Byte) | Dec. Offset (Byte) |
|-----------------------------|--------------------------|----------------|--------------|-------------------------|-----------------------|
| MLC Device health status | MLC_DEVICE_HEALTH_STATUS | 1 | R | 0x5E | 94 |
| SLC Device health status | SLC_DEVICE_HEALTH_STATUS | 1 | R | 0x57 | 87 |

2.13. Enhanced Write Protection

To allow the host to protect data against erase or write, the iNAND supports two levels of write protect command¹¹:

- The entire iNAND (including the Boot Area Partitions, General Purpose Area Partition, and User Area Partition) may be write-protected by setting the permanent or temporary write protect bits in the CSD.
- Specific segments of the iNAND may be permanently, power-on or temporarily write protected. Segment size can be programmed via the EXT_CSD register.

For additional information please refer JESD84-B451 standard.

2.14. High Priority Interrupt (HPI)

Many operating-systems use demand-paging to launch a process requested by the user. If the host needs to fetch pages while in a middle of a write operation the request will be delayed until the completion of the write command.

_

¹¹ For additional information refer to JEDEC Standards No. JESD84-B451

The high priority interrupt (HPI) as defined in JESD84-B451 enables low read latency operation by suspending a lower priority operation before it is actually completed. This mechanism can reduce read latency, in typical condition to below 10msec.

For additional information on the HPI function, refer to JESD84-B451 standard section 6.6.23

2.15. H/W Reset

Hardware reset may be used by host to reset the device, moving the device to a Pre-idle state and disabling the power-on period write protect on blocks that was set as power-on write protect before the reset was asserted. For more information, refer to JESD84-B451 standard.

2.16. DDR I/F

Support DDR signaling to double bus performance. For additional information please refer to JESD84-B451 standard.

3. PRODUCT SPECIFICATIONS

3.1. Typical Power Requirements

Table 3.1 - iNAND Sleep Power Requirements (Ta=25°C@3.3V)

| | | Max Value | Measurement |
|---------------------|---------------------|-----------------------|-------------|
| Auto Sleep mode | | 350 | uA |
| Sleep (CMD5 - VCCQ) | | 200 (Max) | uA |
| Read | RMS | 4GB: 150 8GB: 150 | mA |
| | Peak | 4GB: 200 8GB: 250 | mA |
| Write | RMS | 4GB: 100 8GB: 150 | mA |
| | Peak | 4GB: 200 8GB: 250 | mA |
| VCC (rip | ple: max, 100mV pea | k-to-peak) 2.7 V – 3. | 6 V |

Table 4.2 - iNAND Active Power Requirements RMS VCC / VCCQ (Ta=25°C@3.3V)

| Read | RMS VCC | 4GB: 40 8GB: 45 | mA |
|-------|----------|----------------------|----|
| | RMS VCCQ | 4GB: 105 8GB: 105 | mA |
| Write | RMS VCC | 4GB: 40 8GB: 50 | mA |
| | RMS VCCQ | 4GB: 40 8GB: 40 | mA |

- Note 1: RMS Current measurements are average over 100 mSecs.
- Note 2: Sleep current is measured at room temperature
- Note 3: In sleep state, triggered by CMD5, Flash Vcc power supply is switched off
- Note 4: Peak current is measured over 3 uSecs.

3.2. Operating Conditions

3.2.1. Operating and Storage Temperature Specifications

Table 5 - Operating and Storage Temperatures

| Temperature | Operating | -25° C to 85° C | |
|-------------|---|-----------------|--|
| | Non-Operating: After soldered onto PC Board | -40° C to 85° C | |

3.2.2. Moisture Sensitivity

The moisture sensitivity level for iNAND is MSL = 3.

3.3. System Performance

All performance values for iNAND in Table 6 were measured under the following conditions:

• Voltage range:

Core voltage (VCC): 2.7-3.6v

Host voltage (VCCQ), either: 1.7-1.95v or 2.7-3.6v

• Operating temperature -25° C to 85° C

Table 6a – Sequential System Performance

| SKU | Sustained Write | Sustained Read |
|-------------|-----------------|----------------|
| SDIN7DP2-4G | 12MB/s | 90MB/s |
| SDIN7DP2-8G | 24MB/s | 90MB/s |

Note 1: Sustained Read & Write performance is measured under DDR Bus width of 8bit at 52Mhz.

Table 7b – Random System Performance

| SKU | Sustained Write | Sustained Read |
|-------------|-----------------|----------------|
| SDIN7DP2-4G | 400 IOPS | 2500 IOPS |
| SDIN7DP2-8G | 500 IOPS | 2500 IOPS |

Note 2: Sustained Read & Write performance is measured using SanDisk proprietary test environment, w/o FS overhead.

Table 5c - System Timing Performance

| Timing | Value | |
|------------------------------------|---------|--|
| Block Read Access Time (MAX) | 100 ms | |
| Block Write Access Time (MAX) | 250 ms | |
| CMD1 to Ready after Power-up (MAX) | 1000 ms | |

4. PHYSICAL SPECIFICATIONS

The SanDisk iNAND is a 153 pin, thin fine-pitched ball grid array (BGA). See Figure 2, Figure 3 and Table 8 for physical specifications and dimensions.

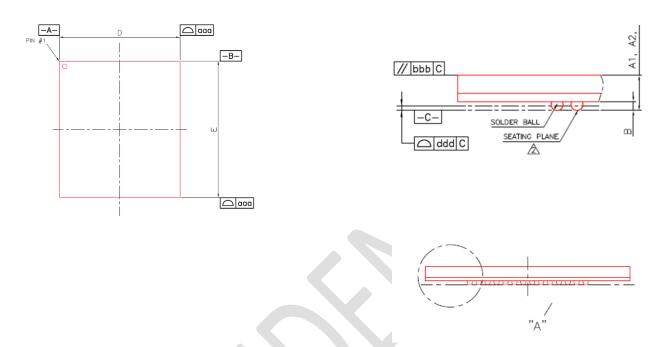


Figure 2- INAND Specification Top and Side View (Detail A)

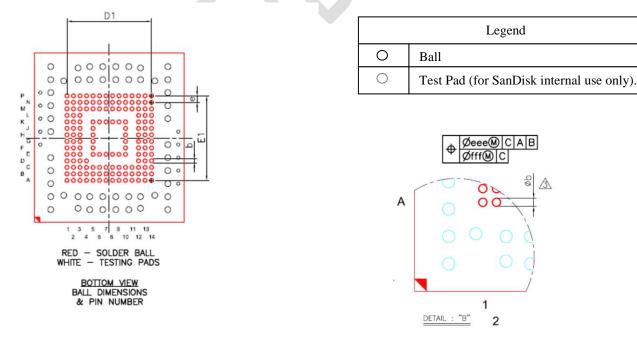


Figure 3- Package Outline Drawing - bottom view

Table 8 - iNAND Package Specification

| 153 ba | all | Dimens | Dimension in millimeters | | | ension in ir | nches |
|-----------------|--------|---------|--------------------------|---------|---------|--------------|---------|
| Package Size | Symbol | Minimum | Nominal | Maximum | Minimum | Nominal | Maximum |
| 11.5X13X1.0 | A1 | | | 1.00 | | | 0.039 |
| All | В | 0.17 | 0.22 | 0.27 | 0.007 | 0.009 | 0.011 |
| All | D | 11.40 | 11.50 | 11.60 | 0.449 | 0.453 | 0.457 |
| All | Е | 12.90 | 13.00 | 13.10 | 0.508 | 0.512 | 0.516 |
| All | D1 | | 6.50 | | | 0.256 | |
| All | E1 | | 6.50 | | | 0.256 | |
| All | е | | 0.50 | | | 0.020 | |
| All | В | 0.25 | 0.30 | 0.35 | 0.010 | 0.012 | 0.014 |
| All | Aaa | 0.10 | 0.004 | | | | |
| All | Bbb | 0.10 | | | | 0.004 | |
| All | Ddd | 0.08 | | | 0.003 | | |
| All | MD/ME | 14/14 | | | 14/14 | | |

5. INTERFACE DESCRIPTION

5.1. MMC I/F Ball Array 153 ball

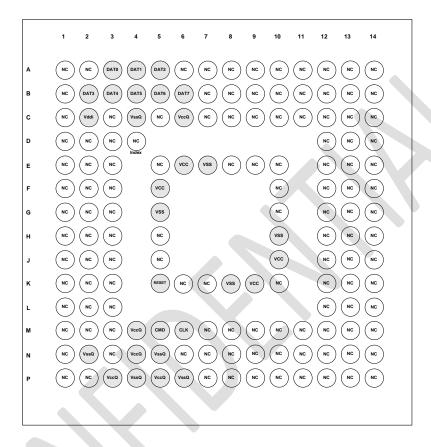


Figure 4 - 153 balls - Ball Array (Top View)

5.2. Pins and Signal Description 153 balls

 $Table\ 7a\ contains\ the\ SanDisk\ iNAND\ \textit{Ulta},\ with\ MMC\ interface,\ functional\ pin\ assignment.$

Table 7a - Functional Pin Assignment

| Ball No. | Ball Signal | Туре | Description | | | |
|----------|-------------|---------------------------------------|--|--|--|--|
| A3 | DAT0 | , , , , , , , , , , , , , , , , , , , | · | | | |
| A4 | DAT1 | - | | | | |
| A5 | DAT2 | - | | | | |
| B2 | DAT3 | - | | | | |
| B3 | DAT4 | I/O | Data I/O: Bidirectional channel used for data transfer | | | |
| B4 | DAT5 | | | | | |
| B5 | DAT6 | | | | | |
| B6 | DAT7 | | | | | |
| M5 | CMD | I/O | Command: A bidirectional channel used for device initialization and command transfers. | | | |
| M6 | CLK | Input | Clock: Each cycle directs a 1-bit transfer on the command and DAT lines | | | |
| K5 | RST_n | | Hardware Reset | | | |
| E6 | VCC | | | | | |
| F5 | VCC | 0 | Flash VO and an arrangement | | | |
| J10 | VCC | Supply | Flash I/O and memory power supply | | | |
| K9 | VCC | | | | | |
| C6 | VCCQ | | | | | |
| M4 | VCCQ | | | | | |
| N4 | VCCQ | Supply | Memory controller core and MMC I/F I/O power supply | | | |
| P3 | VCCQ | | | | | |
| P5 | VCCQ | | | | | |
| E7 | VSS | | | | | |
| G5 | VSS | Supply | Flash I/O and memory ground connection | | | |
| H10 | VSS | Supply | Plasti i/O and memory ground connection | | | |
| K8 | VSS | | | | | |
| C4 | VSSQ | | | | | |
| N2 | VSSQ | | | | | |
| N5 | VSSQ | | Memory controller core and MMC I/F ground connection | | | |
| P4 | VSSQ | | | | | |
| P6 | VSSQ | | | | | |
| C2 | VDDi | | Internal power node. Connect 0.1uF capacitor from VDDi to ground | | | |

Note: All other pins are not connected [NC] and can be connected to GND or left floating.

5.3. iNAND Registers

5.3.1. OCR Register

Value: 0xC0FF8080

Note: Bit 30 is set because the device is High Capacity; bit 31 will be set only when the device is

ready

| Parameter | OCR slice | Description | Value | Width |
|-------------|-----------|-----------------------|------------|-------|
| Access Mode | [30:29] | Access mode | 10b | 2 |
| | [23:15] | VDD: 2.7 - 3.6 range | 111111111b | 9 |
| | [14:8] | VDD: 2.0 - 2.6 range | 0000000b | 7 |
| | [7] | VDD: 1.7 - 1.95 range | 1b | 1 |

5.3.2. CID Register

| Parameter | CID slice | Description | Value | Width |
|-------------------|-----------|-----------------------|---------------------------------|-------|
| MID | [127:120] | Manufacturer ID | 45h | 8 |
| CBX | [113:112] | Device BGA | 01h | 2 |
| OID | [111:104] | OEM/Application ID | 0000h | 8 |
| PNM | [103:56] | Product name | 4GB: 53454d313647h ("SEM04G") | 48 |
| | | | 8GB: 53454d333247h ("SEM08G") | |
| PRV | [55:48] | Product revision | Counter to indicate FW revision | 8 |
| PSN | [47:16] | Product serial number | Random by Production | 32 |
| MDT ¹² | [15:8] | Manufacturing date | month, year | 8 |
| CRC | [7:1] | CRC7 checksum | 0000000Ь | 7 |

5.3.3. DSR Register

| Parameter | DSR slice | Description | Value | Width |
|-----------|-----------|-------------|-------|-------|
| RSRVD | [15:8] | Reserved | 04h | 8 |
| RSRVD | [7:0] | Reserved | 04h | 8 |

DSR is not implemented; in case of read, value of 0x0404 will be returned.

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¹² Compatible to JESD84-B451

5.3.4. CSD Register

| Parameter | CSD Slice | Description | Value | Width |
|--------------------|-----------|--|----------|-------|
| CSD_STRUCTURE | [127:126] | CSD structure | 11b | 3 |
| SPEC_VERS | [125:122] | System specification version | 0100b | 4 |
| TAAC | [119:112] | Data read access-time 1 | 0Fh | 8 |
| NSAC | [111:104] | Data read access-time 2 in CLK cycles (NSAC*100) | 00h | 8 |
| TRAN_SPEED | [103:96] | Max. bus clock frequency | 32h | 8 |
| CCC | [95:84] | Device command classes | 0F5h | 12 |
| READ_BL_LEN | [83:80] | Max. read data block length | 9h | 4 |
| READ_BL_PARTIAL | [79:79] | Partial blocks for read allowed | 0b | 1 |
| WRITE_BLK_MISALIGN | [78:78] | Write block misalignment | 0b | 1 |
| READ_BLK_MISALIGN | [77:77] | Read block misalignment | 0b | 1 |
| DSR_IMP | [76:76] | DSR implemented | 0b | 1 |
| C_SIZE | [73:62] | Device size | FFFh | 12 |
| VDD_R_CURR_MIN | [61:59] | Max. read current @ VDD min | 111b | 3 |
| VDD_R_CURR_MAX | [58:56] | Max. read current @ VDD max | 111b | 3 |
| VDD_W_CURR_MIN | [55:53] | Max. write current @ VDD min | 111b | 3 |
| VDD_W_CURR_MAX | [52:50] | Max. write current @ VDD max | 111b | 3 |
| C_SIZE_MULT | [49:47] | Device size multiplier | 111b | 3 |
| ERASE_GRP_SIZE | [46:42] | Erase group size | 11111b | 5 |
| ERASE_GRP_MULT | [41:37] | Erase group size multiplier | 11111b | 5 |
| WP_GRP_SIZE | [36:32] | Write protect group size | 11111b | 5 |
| WP_GRP_ENABLE | [31:31] | Write protect group enable | 1b | 1 |
| DEFAULT_ECC | [30:29] | Manufacturer default | 00b | 2 |
| R2W_FACTOR | [28:26] | Write speed factor | 10b | 3 |
| WRITE_BL_LEN | [25:22] | Max. write data block length | 9h | 4 |
| WRITE_BL_PARTIAL | [21:21] | Partial blocks for write allowed | 0b | 1 |
| CONTENT_PROT_APP | [16:16] | Content protection application | 0b | 1 |
| FILE_FORMAT_GRP | [15:15] | File format group | 0b | 1 |
| COPY | [14:14] | Copy flag (OTP) | 1b | 1 |
| PERM_WRITE_PROTECT | [13:13] | Permanent write protection | 0b | 1 |
| TMP_WRITE_PROTECT | [12:12] | Temporary write protection | 0b | 1 |
| FILE_FORMAT | [11:10] | File format | 00b | 2 |
| ECC | [9:8] | ECC code | 00b | 2 |
| CRC | [7:1] | Calculated CRC | 0000000b | 7 |

5.3.5. EXT_CSD Register

| Parameter | ECSD slice [bytes] | Description | Value |
|------------------------|-----------------------|---|---------------------|
| S_CMD_SET | [504] | Supported Command Sets | 1h |
| HPI_FEATURES | [503] | HPI Features | 1h |
| BKOPS_SUPPORT | [502] | Background operations support | 1h |
| MAX_PACKED_READS | [501] | Max packed read commands | 3Fh |
| MAX_PACKED_WRITES | [500] | Max packed write commands | 3Fh |
| DATA_TAG_SUPPORT | [499] | Data Tag Support | 1h |
| TAG_UNIT_SIZE | [498] | Tag Unit Size | 3h |
| TAG_RES_SIZE | [497] | Tag Resources Size | 3h |
| CONTEXT_CAPABILITIES | [496] | Context management capabilities | 5h |
| LARGE_UNIT_SIZE_M1 | [495] | Large Unit size | 0h |
| EXT_SUPPORT | [494] | Extended partitions attribute | 0h |
| | | support | |
| CACHE_SIZE | [252:249] | Cache size | 0000h |
| GENERIC_CMD6_TIME | [248] | Generic CMD6 timeout | 19h |
| POWER_OFF_LONG_TIME | [247] | Power off notification(long) timeout | 64h |
| BKOPS_STATUS | [246] | Background operations status | Default = 0h |
| | | | Updated in Run time |
| CORRECTLY_PRG_SECTORS_ | [245:242] | Number of correctly programmed | Default = 0h |
| NUM | | sectors | Updated in Run time |
| INI_TIMEOUT_AP | [241] | 1st Initialization time after partitioning | Ah |
| PWR_CL_DDR_52_360 | [239] | Power class for 52MHz, DDR at 3.6V | 4GB = 0h |
| | | | 8GB = 22h |
| PWR_CL_DDR_52_195 | [238] | Power class for 52MHz, DDR at 1.95V | 0h |
| PWR_CL_200_195 | [237] | Power class for 200MHz at 3.6V | 0h |
| PWR_CL_200_130 | [236] | Power class for 200MHz, at 1.95V | 0h |
| MIN_PERF_DDR_W_8_52 | [235] | Minimum Write Performance for 8bit at 52MHz in DDR mode | 0h |
| MIN_PERF_DDR_R_8_52 | [234] | Minimum Read Performance for 8bit at 52MHz in DDR mode | 0h |
| TRIM_MULT | [232] | TRIM Multiplier | Eh |
| SEC_FEATURE_SUPPORT | [231] | Secure Feature support | 55h |
| SEC_ERASE_MULT | [230] | Secure Erase Multiplier | 44h |
| SEC_TRIM_MULT | [229] | Secure TRIM Multiplier | 44h |
| BOOT_INFO | [228] | Boot Information | 7h |
| BOOT_SIZE_MULT | [226] | Boot partition size | 10h |
| ACCESS_SIZE | [225] | Access size | 8h |
| HC_ERASE_GROUP_SIZE | [224] | High Capacity Erase unit size | Table 8 |

| Parameter | ECSD slice [bytes] | Description | Value |
|-----------------------|-----------------------|---|----------------------------------|
| ERASE_TIMEOUT_MULT | [223] | High capacity erase time out | Eh |
| REL_WR_SEC_C | [222] | Reliable write sector count | 1h |
| HC_WP_GRP_SIZE | [221] | High capacity write protect group size | Table 8 |
| S_C_VCC | [220] | Sleep current [VCC] | 8h |
| S_C_VCCQ | [219] | Sleep current [VCCQ] | 7h |
| S_A_TIMEOUT | [217] | Sleep/Awake time out | 13h |
| SEC_COUNT | [215:212] | Sector count | Table 9 |
| MIN_PERF_W_8_52 | [210] | Minimum Write Performance for 8bit @52MHz | Ah |
| MIN_PERF_R_8_52 | [209] | Minimum Read Performance for 8bit @52MHz | Ah |
| MIN_PERF_W_8_26_4_52 | [208] | Minimum Write Performance for 4bit @52MHz or 8bit @26MHz | Ah |
| MIN_PERF_R_8_26_4_52 | [207] | Minimum Read Performance for 4bit @52MHz or 8bit @26MHz | Ah |
| MIN_PERF_W_4_26 | [206] | Minimum Write Performance for 4bit @26MHz | Ah |
| MIN_PERF_R_4_26 | [205] | Minimum Read Performance for 4bit @26MHz | Ah |
| PWR_CL_26_360 | [203] | Power Class for 26MHz @ 3.6V | 4GB: 00h 8GB: 22h |
| PWR_CL_52_360 | [202] | Power Class for 52MHz @ 3.6V | 4GB: 00h 8GB: 22h |
| PWR_CL_26_195 | [201] | Power Class for 26MHz @ 1.95V | 0h |
| PWR_CL_52_195 | [200] | Power Class for 52MHz @ 1.95V | 0h |
| PARTITION_SWITCH_TIME | [199] | Partition switching timing | 3h |
| OUT_OF_INTERRUPT_TIME | [198] | Out-of-interrupt busy timing | 19h |
| DRIVER_STRENGTH | [197] | I/O Driver Strength | 1h |
| DEVICE_TYPE | [196] | Device Type | 7h |
| CSD_STRUCTURE | [194] | CSD Structure Version | 2h |
| EXT_CSD_REV | [192] | Extended CSD Revision | 6h |
| CMD_SET | [191] | Command Set | Default = 0h Updated in Run time |
| CMD_SET_REV | [189] | Command Set Revision | 0h |
| POWER_CLASS | [187] | Power Class | 4GB = 0h 8GB = 2h |
| HS_TIMING | [185] | High Speed Interface Timing | Default = 0h Updated in Run time |
| BUS_WIDTH | [183] | Bus Width Mode | Default = 0h |

| Parameter | ECSD slice [bytes] | Description | Value |
|----------------------|-----------------------|---|---------------------|
| | | | Updated in Run time |
| ERASE_MEM_CONT | [181] | Content of explicit erased memory range | 0h |
| PARTITION_CONFIG | [179] | Partition Configuration | Default = 0h |
| | | | Updated in Run time |
| BOOT_CONFIG_PROT | [178] | Boot config protection | Default = 0h |
| | | | Updated in Run time |
| BOOT_BUS_CONDITIONS | [177] | Boot bus width1 | Default = 0h |
| | | | Updated in Run time |
| ERASE_GROUP_DEF | [175] | High-density erase group definition | Default = 0h |
| | | | Updated in Run time |
| BOOT_WP_STATUS | [174] | Boot write protection status | Default = 0h |
| | | registers | Updated in Run time |
| BOOT_WP | [173] | Boot area write protect register | 0h |
| USER_WP | [171] | User area write protect register | 0h |
| FW_CONFIG | [169] | FW Configuration | 0h |
| RPMB_SIZE_MULT | [168] | RPMB Size | 10h |
| WR_REL_SET | [167] | Write reliability setting register | 1Fh |
| WR_REL_PARAM | [166] | Write reliability parameter register | 5h |
| SANITIZE_START | [165] | Start Sanitize operation | Default = 0h |
| | | | Updated in Run time |
| BKOPS_START | [164] | Manually start background operations | Default = 0h |
| | | | Updated in Run time |
| BKOPS_EN | [163] | Enable background operations handshake | 0h |
| RST_n_FUNCTION | [162] | H/W reset function | Default = 0h |
| | | | Updated by the host |
| HPI_MGMT | [161] | HPI management | Default = 0h |
| | | | Updated by the host |
| PARTITIONING SUPPORT | [160] | Partitioning support | 1h |
| MAX_ENH_SIZE_MULT | [159:157] | Max Enhanced Area Size | N/A |
| PARTITIONS_ATTRIBUTE | [156] | Partitions Attribute | Default = 0h |
| | | | Updated by the host |
| PARTITION_SETTING_ | [155] | Partitioning Setting | Default = 0h |
| COMPLETED | | | Updated by the host |
| GP_SIZE_MULT | [154:143] | General Purpose Partition Size | 0h |
| ENH_SIZE_MULT | [142:140] | Enhanced User Data Area Size | 0h |
| ENH_START_ADDR | [139:136] | Enhanced User Data Start Address | 0h |

| Parameter | ECSD slice [bytes] | Description | Value |
|------------------------------|-----------------------|--|----------------------------------|
| SEC_BAD_BLK_MGMNT | [134] | Bad Block Management mode | 0h |
| TCASE_SUPPORT | [132] | Package Case Temperature is Oh controlled | |
| PERIODIC_WAKEUP | [131] | Periodic Wake-up | 0h |
| PROGRAM_CID_CSD_DDR_SU PPORT | [130] | Program CID/CSD in DDR mode support | 1h |
| VENDOR_SPECIFIC_FIELD | [127:64] | Vendor Specific Fields | reserved |
| NATIVE_SECTOR_SIZE | [63] | Native sector size | 0h |
| USE_NATIVE_SECTOR | [62] | Sector size emulation | 0h |
| DATA_SECTOR_SIZE | [61] | Sector size | 0h |
| INI_TIMEOUT_EMU | [60] | 1st initialization after disabling sector size emulation | 0h |
| CLASS_6_CTRL | [59] | Class 6 commands control | 0h |
| DYNCAP_NEEDED | [58] | Number of addressed group to be Released | 0h |
| EXCEPTION_EVENTS_CTRL | [57:56] | Exception events control | 0h |
| EXCEPTION_EVENTS_STATUS | [55:54] | Exception events status | 0h |
| EXT_PARTITIONS_ATTRIBUTE | [53:52] | Extended Partitions Attribute | 0h |
| CONTEXT_CONF | [51:37] | Context configuration | Default = 0h Updated in Run time |
| PACKED_COMMAND_STATUS | [36] | Packed command status | Default = 0h Updated in Run time |
| PACKED_FAILURE_INDEX | [35] | Packed command failure index | Default = 0h Updated in Run time |
| POWER_OFF_NOTIFICATION | [34] | Power Off Notification | Default = 0h Updated in Run time |
| CACHE_CTRL | [33] | Control to turn the Cache ON/OFF | 0h |
| FLUSH_CACHE | [32] | Flushing of the cache | 0h |

The following table shows the capacity available for user data for the various device capacities:

Table 9: Capacity* for User Data

| Capacity | LBA [Hex] | LBA [Dec] | Capacity [Bytes] |
|-------------|-----------|------------|------------------|
| SDIN7DP2-4G | 0x760000 | 7,733,248 | 3,959,422,976 |
| SDIN7DP2-8G | 0xE90000 | 15,269,888 | 7,818,182,656 |

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Table 10: Write protect group size

| SKU | HC_ERASE_GR OUP_SIZE | HC_WP_GRP_SI ZE | Erase Unit Size [MB] | Write Protect Group Size [MB] |
|-------------|-------------------------|--------------------|-------------------------|----------------------------------|
| SDIN7DP2-4G | 4h | 4h | 2MB | 8MB |
| SDIN7DP2-8G | 4h | 8h | 2MB | 16MB |



6. POWER DELIVERY AND CAPACITOR SPECIFICATIONS

6.1. SanDisk iNAND UltraPower Domains

SanDisk iNAND Ultra has three power domains assigned to VCCQ, VCC and VDDi, as shown in Table 11.

Pin **Power Domain** Comments VCCQ Host Interface Supported voltage ranges: High Voltage Region: 3.3V (nominal) Low Voltage Region: 1.8V (nominal) VCC Memory Supported voltage range: High Voltage Region: 3.3V (nominal) **VDDi** VDDi is the internal regulator connection to an Internal external decoupling capacitor.

Table 11 - Power Domains

6.2. Capacitor Connection Guidelines

6.2.1. VDDi Connections

The VDDi (C2/K2) ball must only be connected to an external capacitor that is connected to VSS. This signal may not be left floating. The capacitor's specifications and its placement instructions are detailed below.

The capacitor is part of an internal voltage regulator that provides power to the controller.

Caution: Failure to follow the guidelines below, or connecting the VDDi ball to any external signal or power supply, may cause the device to malfunction.

The trace requirements for the VDDi (C2/K2) ball to the capacitor are as follows:

• Resistance: <2 ohm

• Inductance: <5 nH

The capacitor requirements are as follows:

• Capacitance: >=0.1 uF

• Voltage Rating: >=6.3 V

• Dielectric: X7R or X5R

6.2.2. VCC and VCCQ Connections

- All VCC balls should be connected to a 3.3V supply
- All VCCQ balls should be connected either to a 3.3V or 1.8V supply

SanDisk recommends providing separate bypass capacitors for each power domain as shown in Figure 5.

Note: Signal routing in the diagram is for illustration purposes only and the final routing depends on your PCB layout. Also, for clarity, the diagram does not show the VSS connection. All balls marked VSS should be connected to a ground (GND) plane.

14 13 12 11 10 9 8 Top √iew 7 E6 Vcc 6 5 4 3 2 1 В D E K VccQ Vcc = 3.3V (nom)Trace Requirements (C_5): power Resistance < 2 ohm supply Inductance < 5nH Capacitor C_5: VSS VSS VSS VSS VSS C_1=C_3>=4.7uF Capacitance >= 0.1uF Voltage >= 6.3V C_2=C_4<=100nF Close to Close to Dielectric: X7R or X5R Ball F5 Ball P3

Figure 5- Recommended Power Domain Connections

7. MARKING

First row: Simplified SanDisk Logo

Second row: Sales item P/N

Third row: Country of origin i.e. 'TAIWAN' or 'CHINA'

* No ES marking for product in mass production.

Fourth row: Y- Last digit of year

WW- Work week

D- A day within the week.

MTLLXXX - Internal use

2D barcode: Store the 10 Digital unique ID information as reflected in the fourth row.

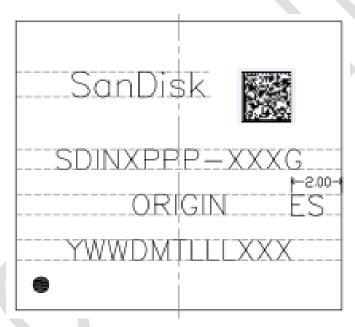


Figure 6: Product marking

80-36-03494

8. ORDERING INFORMATION

Table 12 - Ordering Information

| Capacity | Technology | Part Number | Samples Part Number | Package |
|----------|------------|-------------|------------------------|--------------------------|
| 4GB | X2 | SDIN7DP2-4G | SDIN7DP2-4G-Q | 11.5mm x 13mm x 1.0mm |
| 8GB | X2 | SDIN7DP2-8G | SDIN7DP2-8G-Q | 11.5mm x 13mm x 1.0mm |

Note 1: Suffix "T" added to the P/N indicates tape/reel. For example, SDIN7DP2-8G would become SDIN7DP2-8G-T. The default P/Ns in Table 10 are shipped in trays.

Note 2: Optional Customer Code in case applicable will be added at the end of the part number. For example SDIN7DP2-8G-999 or SDIN7DP2-8G-999Q

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